Notice of References Cited Application/Control No. 10/621,165 Examiner Viet Q. Nguyen Applicant(s)/Patent Under Reexamination LEE ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,836,104	12-2004	Yoshihara, Kazuo	323/314
	В	US-5,912,856	06-1999	Lee et al.	365/226
	O	US-6,861,872	03-2005	Suh, Jungwon	326/62
	D	US-6,661,279	12-2003	Yabe, Tomoaki	327/546
	Е	US-5,570,005	07-1996	Hardee et al.	424/59
	F	US-2003/0214278	11-2003	Yoshihara, Kazuo	323/314
	G	US-			
	Н	US-			
	I	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP02002237186A	08-2002	Japan	Horiguchi et al	G11C 11/407
	0	JP411231951A	08-1999	Japan	Don	G05F 1/56
	Ρ	JP411202955A	07-1999	Japan		
	σ					
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
	V					
	w					
	x					

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.